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Notice of Allowability	Application No.	Applicant(s)	
	10/765,911	CAMPBELL ET AL.	
	Examiner	Art Unit	
	Thinh T. Nguyen	2818	·
The MAILING DATE of this communication apperall claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI	(OR REMAINS) CLOSED in this or other appropriate communica GHTS. This application is subje	s application. If not include ation will be mailed in due	ed course. THIS
1. This communication is responsive to 11/15/2005.			
2. 🔀 The allowed claim(s) is/are <u>1-77</u> .			
3. Acknowledgment is made of a claim for foreign priority una   All   b) Some*   c) None   No	been received.  been received in Application Notuments have been received in some of this communication to file a releast of this application.  itted. Note the attached EXAMINES reason(s) why the oath or decit be submitted.  on's Patent Drawing Review ( Passes Amendment / Comment or in the decite header according to 37 CFR 1.	this national stage applicated in the control of th	quirements OTICE OF
Attachment(s)  1.  Notice of References Cited (PTO-892)  2.  Notice of Draftperson's Patent Drawing Review (PTO-948)  3.  Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date  4.  Examiner's Comment Regarding Requirement for Deposit of Biological Material	6.  Interview Summ Paper No./Mail 8), 7.  Examiner's Ame 8.  Examiner's Stat 9.  Other	Date	

Supervisory Patent Examiner Technology Center 2800 Application/Control Number: 10/765,911

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**DETAILED ACTION** 

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Reason for allowance

1. Claims 1-77 are allowed. The following is an examiner's statement of reason for

allowance:

I/ Group I: Claims 1-18:

None of the references of record teaches or suggests the claimed NON-

VOLATILE ZERO FIELD SPLITTING RESONANCE MEMORY having the

limitations:

-- "a host material layer, said host material layer exhibiting zero field splitting

and being configured to store data as an energy-absorbing state and a lesser-

energy-absorbing state; and a first electrode and a second electrode, each being

electrically coupled to said host material layer "--

and all other limitations as recited in claim 1.

II/ Group II: Claims 19-26:

None of the references of record teaches or suggests the claimed NON-

**VOLATILE ZERO FIELD SPLITTING RESONANCE MEMORY** having the limitations:

-- "A zero-field splitting memory device, comprising:

a first electrode; a germanium selenide layer in contact with said first electrode,

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said germanium selenide layer having a stoichiometry of Ge x Se 100-x;

metal ions incorporated into said germanium selenide layer, wherein said

germanium selenide and said metal ions are configured to absorb a detectable

amount of energy when said memory device is programmed to an energy-

absorbing state "---

and all other limitations as recited in claim 19.

III/ Group III: Claims 27-41:

None of the references of record teaches or suggests the claimed NON-

**VOLATILE ZERO FIELD SPLITTING RESONANCE MEMORY** having the limitations:

-- "a host material incorporating a plurality of different metal ion types, said

each of said different metal ion types exhibiting zero field splitting, said host

material and said different metal ion types being configured to store data as a

plurality of energy-absorbing states and a non-energy-absorbing state; and

a first electrode and a second electrode, each being electrically coupled to

said host material. "-

and all other limitations as recited in claim 27.

IV/ Group IV: Claims 42-46:

None of the references of record teaches or suggests the claimed NON-

**VOLATILE ZERO FIELD SPLITTING RESONANCE MEMORY** having the limitations:

-- "a memory cell, comprising:

a host material incorporating metal ions, said metal ions exhibiting zero field

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splitting and said host material being configured to store data as an energy-absorbing state and a non-energy-absorbing state; and a first electrode and a second electrode, each being electrically coupled to said host material. "—
and all other limitations as recited in claim 42.

V/ Group V: Claims 47-61:

None of the references of record teaches or suggests the claimed NON-

## **VOLATILE ZERO FIELD SPLITTING RESONANCE MEMORY** having the limitations:

-- "providing a memory device comprising a host material which incorporates metal ions exhibiting zero field splitting; programming said memory device to an energy-absorbing state corresponding to a separation of spin states of said metal ions at zero magnetic field; and reading said memory device by sensing the absorption or transmission of a read energy pulse through said host material "— and all other limitations as recited in claim 47.

VI/ Group VI: Claims 62-77:

None of the references of record teaches or suggests the claimed NON-VOLATILE ZERO FIELD SPLITTING RESONANCE MEMORY having the limitations:

-- "providing a memory cell comprising a host material which incorporates a plurality of metal ion species, each said species exhibiting zero field splitting; programming said memory cell to at least one of a plurality of energy-

absorbing states, each said energy-absorbing state corresponding to a separation of spin states of a respective one of said plurality of metal ion species at zero magnetic field; and reading said memory device by sensing the absorption or transmission of one

of a plurality of read energy pulses through said host material, said one read energy pulse corresponding to said respective one metal ion species "— and all other limitations as recited in claim 62.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance".

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## Conclusion

2. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Thinh T Nguyen whose telephone number is 571-272-1790. The examiner can normally be reached on Monday-Friday 9:00am-6:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms can be reached at 571-272-1787. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval [ PAIR ] system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Thinh T Nguyen

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**Supervisory Patent Examiner** Technology Center 2800

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